

4/16/07

SHEET 1 OF A1

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 243028US0DIV	SERIAL NO. NEW APPLICATION		
LIST OF REFERENCES CITED BY APPLICANT		OPIE APR 18 2007 RECEIVED U.S. PATENT AND TRADEMARK OFFICE		APPLICANT Toshimitsu TETSUI, et al.	161667651		
				FILING DATE HEREWITH	GROUP 1742		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,226,985	07-13-93	Y-W. KIM et al.			
	AB	5,338,729	09-24-96	Y-W. KIM, et al.			
	AC	5,442,847	08-22-95	S.L. SEMIATIN, et al.			
	AD	5,846,351	12-08-98	N. MASAHASHI, et al.			
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
	AO	64-042539	02-14-89	JAPAN	YES	NO	
	AP	1-298127	12-01-89	JAPAN		X	
	AQ	6-049565	02-22-94	JAPAN		X	
	AR	6-041661	02-13-94	JAPAN		X	
Xm	AS	62-000215	01-06-87	JAPAN (no abstract available)		X	
	AT	4-066630	09-09-92	JAPAN		X	
	AU	4-124236	04-24-92	JAPAN		X	
	AV	6-49024	02-22-94	JAPAN		X	
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
AW	D. ZHANG et al., <i>Intermetallics</i> , Vol. 7, No. 10, XP-004177382, pp. 1081-1087, "Characterization of Controlled Microstructures in A TiAl (Cr, Mo, Si, B) ALLOY," October 1999.						
AX	"ASM Handbook: Vol. 3 Alloy Phase Diagrams," ASM International, 1992, p. 254.						
AY							
AZ	<input type="checkbox"/> Additional References sheet(s) attached						
Examiner	Date Considered 7/15/07						
*Examiner: Initial if reference is considered whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

* the above crossed out references have been previously considered